

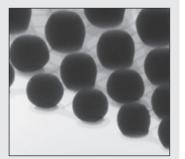
Industrial X-ray and CT



Electronics inspection made easy

There is an increasing demand for flexible, high-resolution and cost-effective X-ray inspection systems to cope with the evolution of ever-shrinking geometries within electronics components and to comply with tighter quality standards.

The XT V series enable insights into printed circuit board assemblies, components, or electrical devices in an intuitive, non-destructive inspection process. X-ray inspection provides many benefits to manufacturers and researchers, accelerating throughput and improving product quality whilst reducing costs.



Head-in-Pillow defect

Top view QFN

SMD (S

BGA (Ba QFN (Qu QFP (Qu

THROU

IC BONE

Wire bor Flip chip C4 (Con Connect

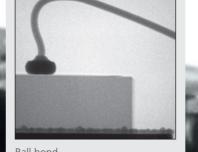
WAFER WLFP O

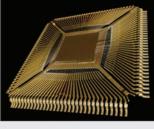
TSV (Thr Micro-bu Cu-pillar

Besides electronics inspection, XT V systems are also suited for X-ray and CT inspection of a wide variety of smaller components. The large tray can hold different samples for serial NDT analysis:

Micro-Electro-Mechanical Systems (MEMS, MOEMS) often used in consumer electronics such as smartphones, these can include accelerometers, pressure sensors, gyroscopes, action buttons, etc.

Series radiographic inspection of small components such as cables, harnesses, plastic parts, LED lights, switches, medical parts, etc.





CT image of package





A wealth of applications

With the constant demand for component miniaturization and 3D packaging technologies, modern X-ray inspection systems must provide the sharpest images and a vast range of applications in order to increase productivity.

URFACE MOUNT DEVICES)		
II Grid Array) ıad-Flat No-leads) ad Flat Package)	 BGA diameter and circularity BGA and PAD array void analysis Head-in-Pillow Cold or dry joint Missing BGA Bridging Form solder connection Solder balls 	
GH-HOLE	- Filling of PTH - Cracks in through holes - Bridging between pins	
DING		
nding (Au or Cu) trolled Collapse Chip tion)	 Broken wire Wire sweep analysis Broken wedge bond Lifted ball bond µBGA void analysis Cold joint Package void analysis 	

R WL-CSP, 3D PACKAGING, SYSTEM IN PACKAGE (SIP)		
rough Silicon Via) umps r	- Voids in Cu filling - Remaining edge fluid - Voids analysis - Cold joint	

At the core of X-ray technology

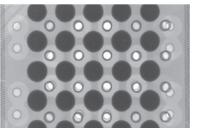
Nikon Metrology X-ray sources are the core of our technology and are designed and manufactured in-house. This allows Nikon Metrology to quickly move with the market and develop complete and innovative solutions to the application demand.

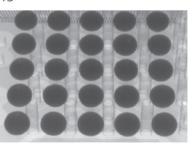
Key benefits include low cost of ownership, lower maintenance and higher reliability through open tube design. The integrated voltage generator eliminates the need for a high voltage cable assembly that requires regular maintenance.

With inherent precision



45°





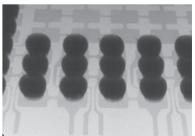
Tilt angles up to 72° offers sufficient flexibility to trace connectivity

The XT V systems are supplied with a highly accurate sample manipulator with an optional precision CT rotate axis.

The vertical system configuration, with the X-ray tube below the sample holder and the tilting imager is controlled through user-friendly Inspect-X software or via precise joystick manipulation.

Capable of multiple rotations even at maximum tilt, the rotate table of the premium XT V 160 provides helicopter fly-around views of any region of interest even at maximum magnification.





XT V 160

PREMIUM X-RAY INSPECTION

Specifically designed for use in production lines and failure analysis laboratories, the XT V 160 can be configured with a choice of premium system components to optimize the performance for your needs. Besides manual real-time inspection, the inspection process can be fully automated to maximize productivity.





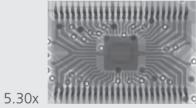
- Various flat panel detector options
- Proprietary NanoTech 160 kV / 20 W microfocus source with submicron feature recognition
- 5-axis manipulator (X,Y,Z, Rotate, Tilt)
- 360° fly-around views while keeping region of interest consistently locked into the center of the field of view
- Real-time imaging or automated inspection
- Ready for CT applications (option)

INTUITIVE TO USE

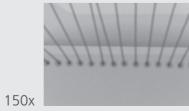
- Intuitive joystick navigation for real-time X-ray inspection
- Collision-free sample manipulation
- Large 30" display for combined system control and real-time analysis
- Industry leading Inspect-X software
- Minimum training requirement operational within 1 day
- Local language support

HIGH-QUALITY IMAGES

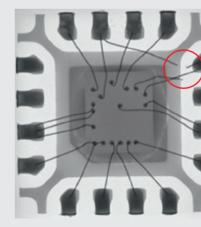
- In-house designed and manufactured microfocus sources
- Up to 2,046x geometric magnification to zoom in on the smallest details
- 500 nm feature recognition on XT V 160
- 16bit image processing
- Max 72° tilt angle to detect cold joints and head-in-pillow
- Accurate control of the power and direction of the emitted X-ray beams







Unparalleled magnification, enables users to zoom in on any region of interest.



Broken bond wire

FOCUS ON PRODUCTIVITY

- reporting

- (optional)

LOW COST OF OWNERSHIP

- replaceable low cost filaments
- Serviceable components are easily accessible
- Integrated source requires no high voltage cable • No special floor treatment required

SAFETY AS A DESIGN CRITERION

- clothing
- standards and CE regulation

XT V 130C

COST-EFFECTIVE X-RAY INSPECTION

The XT V 130C is a highly flexible and costeffective electronics and semiconductor inspection system. The system features a 130 kV/10 W Nikon Metrology manufactured source, a globally recognized open tube design with integrated generator, and a high-resolution imaging chain.

A series of optional factory or field upgrades enable the users to configure the system to their own requirements and budget. Upgrades include a sample rotation stage, a high definition digital flat panel option, automated inspection software and CT technology

- Proprietary 130 kV / 10W microfocus source with 2 µm feature recognition
- 1 megapixel flat panel detector with 127 micron pixel pitch
- 4-axis manipulator (X, Y, Z, Tilt)
- Primarily focusing on real-time imaging

• Fast automated component inspection with immediate analysis and

• Load position for guick and easy loading/unloading of sample

- Large door with automatic interlocked X-ray off function provides easy access to the inspection area
- Large tray to load multiple boards
- Barcode reader for automatic recognition of specimen serial number

• Unlimited source life-time due to open tube design with user

• Continuous fail-to-safe monitoring • Full protective enclosure requires no special badges or protective

• Lead-lined cabinet fully complies to DIN 54113 radiation safety

Real-time inspection with advanced analysis

Interactive and user-friendly software is essential in evaluating the complex internal structures, performing accurate inspection, providing defect recognition with confidence.

Inspect-X has been designed around the user experience, resulting in intuitive and productive X-ray inspection. Inspect-X features user friendly wizards to guide users through complex inspections, as well as utilizing the most advanced visualization and analysis function capabilities. XT V systems with Inspect-X enable rapid deployment of new product lines, within minutes, rather than hours or days.

INSPECT-X CONTROL SOFTWARE

- Workflow based all necessary controls available to the user's workflow
- Various user access levels for supervisors and operators
- Quick access toolbar to most applicable functions
 Minimum training time
- Board map for guick sample overview
- Collision avoidance between all components of the system and sample
- All functions included as standard; no add-on modules required

REAL TIME X-RAY INSPECTION

- On-screen joysticks and mouse gestures, as well as conventional intuitive joystick control, for interactive live part positioning
- Variable magnification and tilted viewing angle allow real time detection of defects such as head-in-pillow.
- Magnification, tilt and rotate in all positions whilst maintaining a region of interest consistently locked into the center of the field of view
- C.Clear imaging engine provides crystal-clear live images
- Real-time imager for interactive visualization



IMAGE ANALYSIS AND ENHANCEMENT

Making real-time correct decisions requires crystal-clear and sharp images. The C.Clear real-time image engine enables operators to identify defects with confidence without time consuming image enhancements.

C.Clear intelligently adapts to changing X-ray conditions and sample positions, automatically adjusting image controls, contrast and brightness in order to provide the clearest and sharpest images to aid in defect recognition.

- Real-time enhancements and filters stored as user profiles to suit different sample types or individual operator preferences.
- Image processing filters (sharpen, smooth, edge detect, emboss, background subtract, etc.)
- Image histogram

BGA DEVICE INSPECTION

The BGA device inspection functionality is an 'all-in-one' tool offering automatic analysis of:

- Voiding (single and total ball percentage)
- Ball circularity
- Ball count
- Bridging
- Pass/Fail detection

With its powerful image processing algorithm, the tool gives accurate results even in complex board assemblies with underside components.

The tool allows creation of an internal library of BGA templates using a wizard or via file import to reduce the time taken to build automated pass/fail inspection routines.

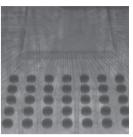
BOND WIRE ANALYSIS

Featuring high magnification and (sub)micron feature detection, the XT V platforms equipped with Inspect-X are a powerful tool for advanced bond wire inspection. The new automated multi-bond wire tool provides repeatable inspection with the highest accuracy.

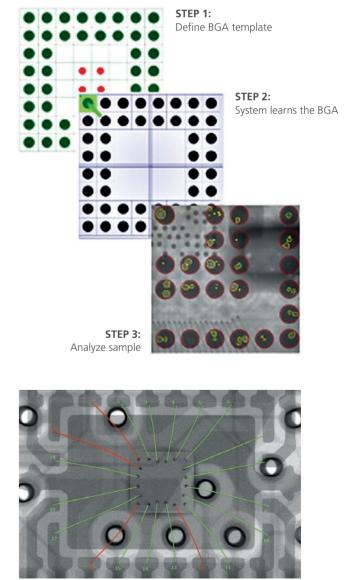
- Identify and detect broken bond wires and wire sweep with pass/fail status
- Automatically analyze multiple bond wires on a device in a single inspection
- Component templates can be saved to an internal library, aiding rapid future builds of inspection routines.



C.Clear improves X-ray image quality to facilitate real-time defect recognition

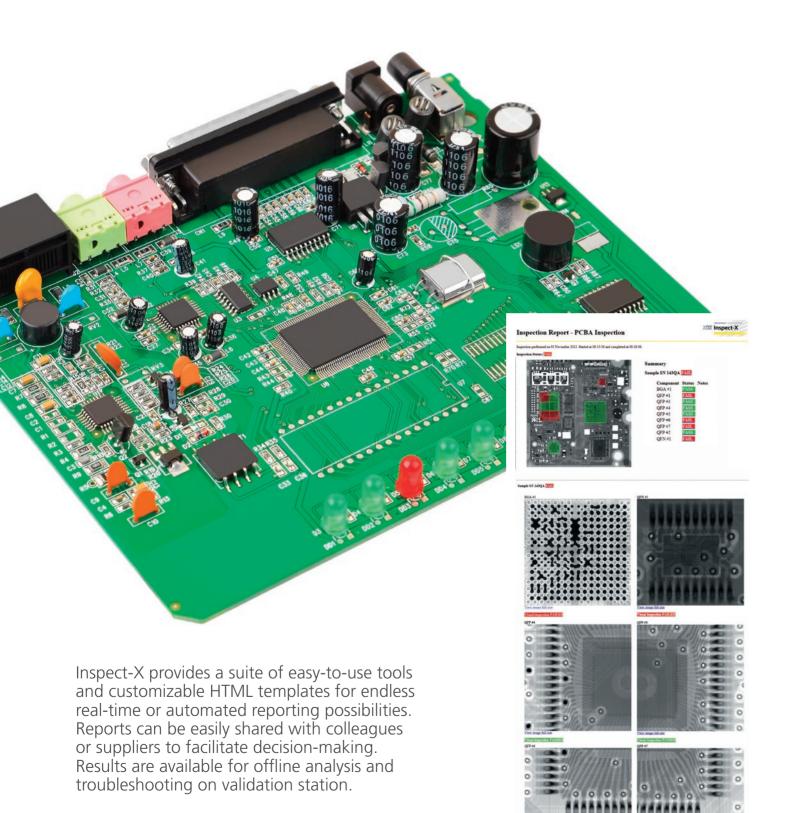


Real-time image without C.Clear



Bond wire analysis

Insightful reporting



Focusing on productivity

Operating in automated inspection mode, the XT V combined with Inspect-X is a productive X-ray solution for repeated inspection of PCBAs, semiconductor components and complex high-density boards. Creation and execution of inspection routines is straightforward, utilizing the graphical interface or teach and learn. Users requiring detailed insight of (multi-layer) electronic components can benefit from the X.Tract or Computed Tomography functionality for a full 3D view of internal structure.

AUTOMATED INSPECTIONS

- Macros for automating simple repetitive tasks
- Automated inspection and analysis of full boards or multiple components
- No programming skills required, utilizing graphical interface or teach and learn
- Intelligent Program Control (IPC) for customizable system control
- Off-line validation station giving maximum efficiency of the X-ray system
- HTML reporting function, readable on any PC with no special software
- Switch seamlessly between radiographic (2D) and CT (3D) modes in one single software
- Visual check during automated inspection allows interactive inspection

SEE MORE WITH X.TRACT

X.Tract provides CT-quality inspection results of complex, multi-layer electronics assemblies without slicing them. In a rapid and user-friendly process, it enables virtual microsections in any direction in the region-of-interest. X.Tract reveals defects that are obscured in 2D X-ray images of complex components such as Package on Package (PoP) or double sided boards. With X.Tract, users gain better insights leading to reduced false call rates and higher productivity.

READY FOR CT

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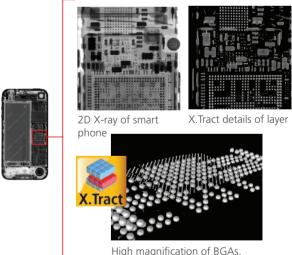
- CT acquisition and analysis as factory option or field upgrade
- Easy, user guided, CT data collection
- Fast Rescan rescan in only two steps
- World-leading reconstruction times
- Automatic reconstruction of CT data streamed from XT V system
- Powerful CT analysis in the software of your choice



Intuitive icons help the user to interactively build an automated inspection routine



Macro-based recording enables the user to program for repeated inspection or batch analysis



High magnification of BGAs, visualized in a 3D representation



Voids in BGA (CT image)

Specifications





	XT V 160	XT V 130C	
Max kV	160 kV	130 kV	
Max. electron beam power	20 W	10 W	
X-ray source	Open tube transmission target		
Focal spot size ^{1,2}	1 µm	3 µm	
Feature recognition ¹	500 nm	2 µm	
Geometric magnification	2,046x		
System magnification	Up to 36,000x		
Imaging system	Varex 2520DX (2.85 Mpixel, 16-bit) Flatpanel Varex 1515DX (1.3 Mpixel, 16-bit) Flatpanel	Varex 1313DX (1 Mpixel, 16-bit) Flatpanel	
Manipulator	5-axis (X, Y, Z, T, R)	4-axis (X, Y, Z, T)	
Rotate axis	Included	Optional	
Tilt	0 - 72 degrees		
Measuring volume	Largest square in single map 406 x 406 mm (16 x 16") Maximum physical sample size 711 x 762 mm (28 x 30")		
Max. sample weight	5 kg (11 lbs)		
Monitor	Single 4k IPS (3,840 x 2,160 pixels)		
Cabinet dimensions (W x D x H)	1,200 x 1,786 x 1,916 mm (48.0 x 71.3 x 75.4")		
Weight	2,100 kg (4,629 lbs)		
Radiation safety	<1 µSv/hr at the cabinet surface		
Control	Inspect-X control and analysis software		
Automated inspection	Included	Optional	
Computed Tomography / X.Tract	Optional		
Primary applications	Real-time and automated electronics and semiconductor inspection, failure analysis	Real-time electronics inspection	

¹ at 80 kV, 80 µA

² below 2 W

Specifications and equipment are subject to change without any notice or obligation on the part of the manufacturer. October 2021

WARNING

TO ENSURE CORRECT USAGE, READ THE CORRESPONDING MANUALS CAREFULLY BEFORE USING THE EQUIPMENT.



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Printed in Japan (2110-02) Am/M

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Code No. 2CE-NNIH-2